

<b>Notice of References Cited</b>	Application/Control No. 10/565,244	Applicant(s)/Patent Under Reexamination CHIBA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,698,315	12-1997	Hayashi et al.	428/336
*	B	US-6,235,443	05-2001	Kayamoto et al.	430/111.1
*	C	US-5,534,193	07-1996	Jacobson, Howard W.	252/520.1
*	D	US-6,211,144	04-2001	Havelund, Svend	514/4
*	E	US-6,632,276	10-2003	Vogt, Reiner	106/417
*	F	US-2006/0188654	08-2006	Onoyama et al.	427/402
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06-092636	06-1993	Japan	Okuda et al.	C01G 19/02
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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